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Resúmenes de comunicaciones

## POS-A22

PD en Física

## VACANCY ORDERING IN MULLITE - A SUPERSPACE MODEL

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Single crystal X-ray diffraction was applied to analyze the reciprocal space of a commercial mullite sample with composition Al4.84Si1.16O9.38 (Z=1) to analyze the vacancy ordering, that was generally believed to be short-range ordered. Sharp satellite reflections were visible in the diffraction patterns. The development of a superspace model required the use of different scaling factors for main and satellite reflections, respectively, indicating that only a fraction of the sample is ordered and a larger fraction is disordered. The main feature of the superspace model is the presence of oxygen vacancies in the expected environment with tetrahedra triclusters. The vacancies group together forming vacancy-dense sections that are separated by vacancy-free sections. These sections alternate along c and along a, which explains the doubling of the c parameter and also the incommensurate modulation along a. The amount of vacancies per vacancy-dense section, i.e. the length of the vacancy-dense sections, varies to match the composition given by the refined vacancy concentration x = 0.426(5). A commensurate approximation with a 17 × 1 × 2 supercell contains 14 vacancies corresponding to a vacancy concentration  $x = 14/34 \approx 0.412$ . We get to the conclusion that long-range order and short-range order coexist in mullite because satellite reflections were not detected in many measurements. Accordingly mullite is mostly disordered and a small, variable amount of domains with a long-range ordered vacancy distribution is present. This explains why satellite reflections in X-ray diffraction patterns are weaker than expected before and also why higher orders are visible in several electron diffraction patterns.

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